Rochester Electronics

Datasheet

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
    - Class Q Military
    - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)

- Rochester is a critical supplier to DLA and meets all industry and DLA standards.

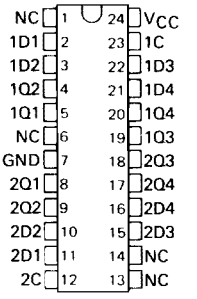
Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

DECEMBER 1972 REVISED DECEMBER 1983

- **Dependable Texas Instruments Quality and Reliability**

SN54100 . . . J OR W PACKAGE
SN74100 . . . J OR N PACKAGE
(TOP VIEW)



NC –No internal connection

description

These latches are ideally suited for use as temporary storage for binary information between processing units and input/output or indicator units. Information present at a data (D) input is transferred to the Q output when the enable (G) is high and the Q output will follow the data input as long as the enable remains high. When the enable goes low, the information (that was setup at the data input at the time the transition occurred) is retained at the Q output until the enable is permitted to go high.

These circuits are completely compatible with all popular TTL families. All inputs are diode-clamped to minimize transmission-line effects and simplify system design. Typical power dissipation is 40 milliwatts per latch.

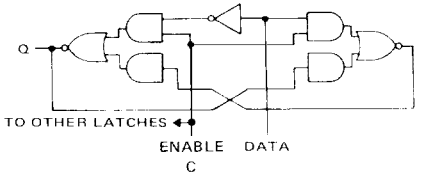
The SN54100 is characterized for operation over the full military temperature range of −55°C to 125°C; the SN74100 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE
(Each Latch)

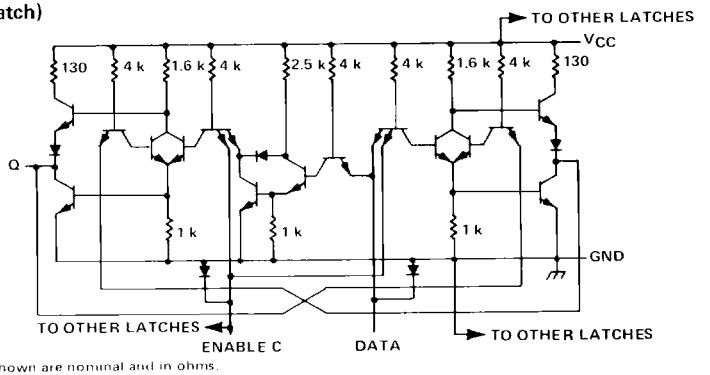
INPUTS		OUTPUTS	
D	G	Q	$\bar{Q}$
L	H	L	H
H	H	H	L
X	L	Q_0	$\bar{Q}_0$

H = high level, X = irrelevant
Q_0 = the level of Q before the high-to-low transition of G

logic diagram (each latch)



schematic (each latch)



Resistor values shown are nominal and in ohms.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage . . . . . 5.5 V
Interemitter voltage (see Note 2) . . . . . 5.5 V
Operating free-air temperature range: SN54100 . . . . . −55°C to 125°C
SN74100 . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

NOTES: 1. Voltage values, except interemitter voltage, are with respect to network ground terminal.
2. This is the voltage between two emitters of a multiple-emitter input transistor. For this circuit, this rating applies between the enable and D inputs of any latch.

recommended operating conditions

	SN54100			SN74100			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V_{CC}	4.5	5	5.5	4.75	5	5.25	V
High-level output current, I_{OH}			−400			−400	μA
Low-level output current, I_{OL}			16			16	mA
Width of enabling pulse, t_w	20			20			ns
Setup time, t_{su}	20			20			ns
Hold time, t_h	5			5			ns
Operating free-air temperature, T_A	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER			TEST CONDITIONS†		MIN	TYP‡	MAX	UNIT
V_{IH}	High-level input voltage				2			V
V_{IL}	Low-level input voltage						0.8	V
V_{IK}	Input clamp voltage		V_{CC} = MIN, I_I = −12 mA				−1.5	V
V_{OH}	High-level output voltage		V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = 0.8 V, I_{OH} = −400 μA		2.4	3.4		V
V_{OL}	Low-level output voltage		V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = 0.8 V, I_{OL} = 16 mA			0.2	0.4	V
I_I	Input current at maximum input voltage		V_{CC} = MAX, V_I = 5.5 V				1	mA
I_{IH}	High-level input current	D input	V_{CC} = MAX, V_I = 2.4 V				80	μA
		C input					320	
I_{IL}	Low-level input current	D input	V_{CC} = MAX, V_I = 0.4 V				−3.2	mA
		C input					−12.8	
I_{OS}	Short-circuit output current§		V_{CC} = MAX	SN54100	−20		−57	mA
				SN74100	−18		−57	
I_{CC}	Supply current		V_{CC} = MAX, See Note 3	SN54100		64	92	mA
				SN74100		64	106	

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡All typical values are at V_{CC} = 5 V, T_A = 25°C.
§Not more than one output should be shorted at a time.
NOTE 3: I_{CC} is tested with all inputs grounded and all outputs open.

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switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER¶	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH}	D	Q	C_L = 15 pF, R_L = 400 Ω, See Note 4		16	30	ns
t_{PHL}					14	25	
t_{PLH}	C	Q			16	30	ns
t_{PHL}					7	15	

¶ t_{PLH} = propagation delay time, low-to-hgih-level output
t_{PHL} = propagation delay time, high-to low-level output
NOTE 4: Load circuits and voltage waveforms are the same as those shown for the '75, '77, 'L75, and 'L77.